

## COMING EVENTS

(\*\*\*) Contact Microscopy Today for further information.

- ✓ Oct 12/14 '92: **IBEX '92** (International Biotechnology Expo & Science Conference). San Francisco, CA. (415)508-0118.
- ✓ Oct 14/16 '92: **Scientific Computing & Automation Conference**. Washington, DC. Bill Adam: (800)222-0289 - X473.
- ✓ Oct 20 '92: **Quality and the Microscopy Lab (M/ME Workshop)**. Newton, MA. Barbara Foster (413)746-6931.
- ✓ Oct 26/30 '92: Three Intensive Short Courses:  
     Scanning Electron Microscopy and X-ray Microanalysis for Materials Science and Semiconductor Technology.  
     Scanning Electron Microscopy and Microanalysis for Polymer Science.  
     Image Analysis and Measurement in Microscopy (STM/AFM)  
     SUNY, New Paltz, NY. Angelos V. Pastis: (914)255-0757.
- ✓ Nov 4/6 '92: **ALEX '92: Analytical Laboratory Equipment Conference**. San Francisco, CA. (\*\*\*)
- ✓ Nov 8/13 '92: AVS Short Courses: **Vacuum Technology, Surface Science and Technology, Thin Films and Coatings, Materials: Processing/Characterization**. Chicago, IL. Margaret Banks: (212)661-9404.
- ✓ Nov 9/11 '92: **Computer-Assisted Image Analysis & Measurement**. Chicago, IL. Bruce Winston/Cindy Allen: (919)515-2261.
- ✓ Nov 16/20 '92: **31st Annual Eastern Analytical Symposium**. Somerset, N.J. (302)738-6218.
- ✓ Nov 30-Dec 4 '92: **Fall Meeting of the MRS**. Boston, MA. (412)367-3003.
- ✓ Dec 2/4 '92: **Modern Materials Analysis (MRS)**. Boston, MA. (412)367-3003.
- ✓ Dec 6/7 '92: **Surface and Thin Film Analysis (MRS)**. Boston, MA. (412)367-3003.
- ✓ January 5/8 '93: **John M. Cowley Symposium on Aspects of Electron Microscopy, Diffraction, Crystallography and Spectroscopy**. Scottsdale, AZ. David J. Smith (602)965-4554; Sharon Willison (602)965-4544; FAX: (602)965-9004.
- ✓ January 11/15 '93: **1993 Winter School on High Resolution Electron Microscopy**. Tempe, AZ. Sharon Willison: (602)965-4544; FAX: (602)965-9004.
- ✓ March 8/12 '93: **PITTCOON '93**. Atlanta, GA. (412)825-3220.
- ✓ March 22/26, 29/April 2, '92: **Practical Aspects of Scanning Electron Microscopy (Univ. of MD Short Course)**. College Park, MD. Tim Mangel: (301)405-6898.
- ✓ April 21/23 '93: **SCANNING '93 Conference**. Orlando, FL. Mary K. Sullivan: (201)818-1010.
- ✓ May 5/7 '93: **1st International Symposium on Computerized Data Standards: Databases, Data Interchange, and Information Systems**. Atlanta, GA. Dorothy Savini: (215)299-5413.
- ✓ June 6/10 '93: **Molecular Microspectroscopy** (9th Annual short course & workshop). Miami Univ., Oxford, OH. (513)529-2873.

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- THE LEHIGH SEM/AEM/SPM COURSES '93**
- ✓ June 14/18 '93: **Basic Course: Scanning Electron Microscopy & X-ray Analysis.**
  - ✓ June 21/25 '93: **Advanced Courses:**
    - 1) Microcharacterization of Electronic Materials, Devices and Packages.
    - 2) Advanced Scanning Imaging.
    - 3) Quantitative X-ray Microanalysis of Bulk Specimens and Particles.
    - 4) AFM, STM and Other Scanned Probe Microscopies.
  - ✓ June 21/24 '93: **Analytical Electron Microscopy.**
  - ✓ June 24/25 '93: **Thin Specimen Preparation.**
- For detailed information, contact Professor Joseph Goldstein: Tel.: (215)758-5133, Fax: (215)758-4244/  
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- ✓ July 11/16 '93: **Microbeam Analysis Annual Meeting**. Los Angeles, CA. Jack Worrall, MAS '93, PO Box 1014, Monrovia, CA 91017-1014.

## New Scanning Infrared Microprobe

Nicolet's IR $\mu$ s scanning infrared microprobe is a new molecular microanalysis system that identifies, quantifies and maps organic and inorganic materials. Developed by Spectra Tech, the IR $\mu$ s combines the benefits of light microscopy, infrared spectroscopy, computerized micropositioning and chemometrics.

The IR $\mu$ s operates in the Windows™ environment making it easy-to-use with four operational modes for proper analysis of a full range of sample types.

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